Renesas Electronics America Inc - R7FS5D97C3A01CFP#AA0 Datasheet

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, IrDA, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	76
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	640K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 3.6V
Data Converters	A/D 19x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LFQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs5d97c3a01cfp-aa0

Table 1.3 System (3 of 3)

Feature	Functional description
Independent Watchdog Timer (IWDT)	The IWDT consists of a 14-bit down-counter that must be serviced periodically to prevent counter underflow. The IWDT provides functionality to reset the MCU or to generate a non-maskable interrupt or interrupt for a timer underflow. Because the timer operates with an independent, dedicated clock source, it is particularly useful in returning the MCU to a known state as a fail safe mechanism when the system runs out of control. The IWDT can be triggered automatically on a reset, underflow, or refresh error, or by a refresh of the count value in the registers. See section 28, Independent Watchdog Timer (IWDT) in User's Manual.

Table 1.4 Event link

Feature	Functional description
Event Link Controller (ELC)	The ELC uses the interrupt requests generated by various peripheral modules as event signals to connect them to different modules, enabling direct interaction between the modules without CPU intervention. See section 19, Event Link Controller (ELC) in User's Manual.

Table 1.5 Direct memory access

Feature	Functional description
Data Transfer Controller (DTC)	A DTC module is provided for transferring data when activated by an interrupt request. See section 18, Data Transfer Controller (DTC) in User's Manual.
DMA Controller (DMAC)	An 8-channel DMAC module is provided for transferring data without the CPU. When a DMA transfer request is generated, the DMAC transfers data stored at the transfer source address to the transfer destination address. See section 17, DMA Controller (DMAC) in User's Manual.

Table 1.6 External bus interface

Feature	Functional description
External buses	• CS area (EXBIU): Connected to the external devices (external memory interface) • SDRAM area (EXBIU): Connected to the SDRAM (external memory interface) • QSPI area (EXBIUT2): Connected to the QSPI (external device interface).

Table 1.7 Timers

Feature	Functional description
General PWM Timer (GPT)	The GPT is a 32-bit timer with 14 channels. PWM waveforms can be generated by controlling the up-counter, down-counter, or up- and down-counter. In addition, PWM waveforms can be generated for controlling brushless DC motors. The GPT can also be used as a general-purpose timer. See section 23, General PWM Timer (GPT) in User's Manual.
Port Output Enable for GPT (POEG)	Use the Port Output Enable for GPT (POEG) function to place the General PWM Timer (GPT) output pins in the output disable state. See section 22, Port Output Enable for GPT (POEG) in User's Manual.
Asynchronous General-Purpose Timer (AGT)	The AGT is a 16-bit timer that can be used for pulse output, external pulse width or period measurement, and counting of external events. This 16-bit timer consists of a reload register and a down-counter. The reload register and the down-counter are allocated to the same address, and can be accessed with the AGT register. See section 25, Asynchronous General-Purpose Timer (AGT) in User's Manual.
Realtime Clock (RTC)	The RTC has two counting modes, calendar count mode and binary count mode, that are controlled by the register settings. For calendar count mode, the RTC has a 100-year calendar from 2000 to 2099 and automatically adjusts dates for leap years. For binary count mode, the RTC counts seconds and retains the information as a serial value. Binary count mode can be used for calendars other than the Gregorian (Western) calendar. See section 26, Realtime Clock (RTC) in User's Manual.

Table 1.8 Communication interfaces (1 of 2)

Feature	Functional description
Serial Communications Interface (SCI)	The SCI is configurable to five asynchronous and synchronous serial interfaces: • Asynchronous interfaces (UART and Asynchronous Communications Interface Adapter (ACIA)) • 8-bit clock synchronous interface • Simple IIC (master-only) • Simple SPI • Smart card interface. The smart card interface complies with the ISO/IEC 7816-3 standard for electronic signals and transmission protocol. Each SCI has FIFO buffers to enable continuous and full-duplex communication, and the data transfer speed can be configured independently using an on-chip baud rate generator. See section 34, Serial Communications Interface (SCI) in User's Manual.
IrDA Interface (IrDA)	The IrDA interface sends and receives IrDA data communication waveforms in cooperation with the SCI1 based on the IrDA (Infrared Data Association) standard 1.0. See section 35, IrDA Interface in User's Manual.
I^2C Bus Interface (IIC)	The three-channel IIC conforms with and provides a subset of the NXP I^2C bus (Inter-Integrated Circuit bus) interface functions. See section 36, I^2C Bus Interface (IIC) in User's Manual.
Serial Peripheral Interface (SPI)	Two independent SPI channels are capable of high-speed, full-duplex synchronous serial communications with multiple processors and peripheral devices. See section 38, Serial Peripheral Interface (SPI) in User's Manual.
Serial Sound Interface Enhanced (SSIE)	The Serial Sound Interface Enhanced (SSIE) peripheral provides functionality to interface with digital audio devices for transmitting I^2S 2ch, 4ch, 6ch, 8ch, WS Continue/Monaural/TDM audio data over a serial bus. The SSIE supports an audio clock frequency of up to 50 MHz, and can be operated as a slave or master receiver, transmitter, or transceiver to suit various applications. The SSIE includes 32-stage FIFO buffers in the receiver and transmitter, and supports interrupts and DMA-driven data reception and transmission. See section 41, Serial Sound Interface Enhanced (SSIE) in User's Manual.
Quad Serial Peripheral Interface (QSPI)	The QSPI is a memory controller for connecting a serial ROM (nonvolatile memory such as a serial flash memory, serial EEPROM, or serial FeRAM) that has an SPI-compatible interface. See section 39, Quad Serial Peripheral Interface (QSPI) in User's Manual.
CAN module (CAN)	The CAN module provides functionality to receive and transmit data using a message-based protocol between multiple slaves and masters in electromagnetically-noisy applications. The CAN module complies with the ISO 11898-1 (CAN 2.0A/CAN 2.0B) standard and supports up to 32 mailboxes, which can be configured for transmission or reception in normal mailbox and FIFO modes. Both standard (11-bit) and extended (29-bit) messaging formats are supported. See section 37, Controller Area Network (CAN) Module in User's Manual.
USB 2.0 Full-Speed Module (USBFS)	Full-Speed USB controller that can operate as a host controller or device controller. The module supports full-speed and low-speed (host controller only) transfer as defined in Universal Serial Bus Specification 2.0. The module has an internal USB transceiver and supports all of the transfer types defined in Universal Serial Bus Specification 2.0. The USB has buffer memory for data transfer, providing a maximum of 10 pipes. Pipes 1 to 9 can be assigned any endpoint number based on the peripheral devices used for communication or based on your system. See section 32, USB 2.0 Full-Speed Module (USBFS) in User's Manual.
USB 2.0 High-Speed Module (USBHS)	High-Speed USB controller that can operate as a host controller or a device controller. As a host controller, the USBHS supports high-speed transfer, full-speed transfer, and low-speed transfer as defined in Universal Serial Bus Specification 2.0. As a device controller, the USBHS supports high-speed transfer and full-speed transfer as defined in Universal Serial Bus Specification 2.0. The USBHS has an internal USB transceiver and supports all of the transfer types defined in Universal Serial Bus Specification 2.0. The USBHS has FIFO buffers for data transfer, providing a maximum of 10 pipes. Any endpoint number can be assigned to pipes 1 to 9, based on the peripheral devices or your system for communication. See section 33, USB 2.0 High-Speed Module (USBHS) in User's Manual.

Table 1.11 Graphics

Feature	Functional description
Graphics LCD Controller (GLCDC)	The GLCDC provides multiple functions and supports various data formats and panels. Key GLCDC features include: • GPX bus master function for accessing graphics data • Superimposition of three planes (single color background plane, graphic 1 plane, and graphic 2 plane) • Support for many types of 32- or 16-bit per pixel graphics data and 8-, 4-, or 1-bit LUT data format • Digital interface signal output supporting a video image size of WVGA or greater. See section 58, Graphics LCD Controller (GLCDC) in User's Manual.
2D Drawing Engine (DRW)	The 2D Drawing Engine (DRW) provides flexible functions that can support almost any object geometry rather than being bound to only a few specific geometries such as lines, triangles, or circles. The edges of every object can be independently blurred or antialiased. Rasterization is executed at one pixel per clock on the bounding box of the object from left to right and top to bottom. The DRW can also raster from bottom to top to optimize the performance in certain cases. In addition, optimization methods are available to avoid rasterization of many empty pixels of the bounding box. The distances to the edges of the object are calculated by a set of edge equations for every pixel of the bounding box. These edge equations can be combined to describe the entire object. If a pixel is inside the object, it is selected for rendering. If it is outside, it is discarded. If it is on the edge, an alpha value can be chosen proportional to the distance of the pixel to the nearest edge for antialiasing. Every pixel that is selected for rendering can be textured. The resulting aRGB quadruple can be modified by a general raster operation approach independently for each of the four channels. The aRGB quadruples can then be blended with one of the multiple blend modes of the DRW. The DRW provides two inputs (texture read and framebuffer read), and one output (framebuffer write). The internal color format is always aRGB (8888). The color formats from the inputs are converted to the internal format on read and a conversion back is made on write. See section 56, 2D Drawing Engine (DRW) in User's Manual.
JPEG Codec (JPEG)	The JPEG Codec (JPEG) incorporates a JPEG codec that conforms to the JPEG baseline compression and decompression standard. This provides high-speed compression of image data and high-speed decoding of JPEG data. See section 57, JPEG Codec (JPEG) in User's Manual.
Parallel Data Capture Unit (PDC)	One PDC unit is provided for communicating with external I/O devices, including image sensors, and transferring parallel data such as an image output from the external I/O device through the DTC or DMAC to the on-chip SRAM and external address spaces (the CS and SDRAM areas). See section 44, Parallel Data Capture Unit (PDC) in User's Manual.

Table 1.12 Data processing

Feature	Functional description
Cyclic Redundancy Check (CRC) calculator	The CRC calculator generates CRC codes to detect errors in the data. The bit order of CRC calculation results can be switched for LSB-first or MSB-first communication. Additionally, various CRC-generating polynomials are available. The snoop function allows monitoring reads from and writes to specific addresses. This function is useful in applications that require CRC code to be generated automatically in certain events, such as monitoring writes to the serial transmit buffer and reads from the serial receive buffer. See section 40, Cyclic Redundancy Check (CRC) Calculator in User's Manual.
Data Operation Circuit (DOC)	The DOC compares, adds, and subtracts 16-bit data. See section 52, Data Operation Circuit (DOC) in User's Manual.
Sampling Rate Converter (SRC)	The SRC converts the sampling rate of data produced by various audio decoders, such as the WMA, MP3, and AAC. Both 16-bit stereo and monaural data are supported. See section 42, Sampling Rate Converter (SRC) in User's Manual.

Pin number					Power, System, Clock, Debug, CAC	Interrupt	I/O port	Extbus		Timers				Communication interfaces											Analog		HMI	
BGA176	LQFP176	LGA145	LQFP144	LQFP100				External bus	SDRAM	AGT	GPT	GPT	RTC	USBFS, CAN	SCI0,2,4,6,8 (30 MHz)	SCI1,3,5,7,9 (30 MHz)	IIC	SPI, QSPI	SSIE	ETHERC (MII) (25 MHz)	ETHERC (RMII) (50 MHz)	USBHS	SDHI	ADC12	DAC12, ACMPHS	CTSU	GLCDC, PDC
G4	108	-	-	-	-	-	PA09	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA08_B
G2	109	-	-	-	-	-	PA10	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA07_B
G3	110	G1	90	62	VCC	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
H3	111	G2	91	63	VSS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
H1	112	H1	92	64	VCL	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
H2	113	-	-	-	-	-	PA01	-	-	-	-	-	-	-	SCK8	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA06_B
H4	114	-	-	-	-	-	PA00	-	-	-	-	-	-	-	TXD8	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA05_B
J4	115	-	-	-	-	-	P607	-	-	-	-	-	-	-	RXD8	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA04_B
J1	116	-	-	-	-	-	P606	-	-	-	-	-	RTCOUT	-	CTS8_RTS8/SS8	-	-	-	-	-	-	-	-	-	-	-	LCD_DATA03_B
J2	117	H2	93	-	-	-	P605	D11[A11/D11]	DQ11	-	-	GTIOC8A	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
J3	118	G4	94	-	-	-	P604	D12[A12/D12]	DQ12	-	-	GTIOC8B	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
K3	119	H3	95	-	-	-	P603	D13[A13/D13]	DQ13	-	-	GTIOC7A	-	-	-	CTS9_RTS9/SS9	-	-	-	-	-	-	-	-	-	-	-
K1	120	J1	96	65	-	-	P602	EBCLK	SDCLK	-	-	GTIOC7B	-	-	-	TXD9	-	-	-	-	-	-	-	-	-	-	LCD_DATA04_A
K2	121	J2	97	66	-	-	P601	WR/WR0	DQM0	-	-	GTIOC6A	-	-	-	RXD9	-	-	-	-	-	-	-	-	-	-	LCD_DATA03_A
L1	122	H4	98	67	CLKOUT/CACREF	-	P600	RD	-	-	-	GTIOC6B	-	-	-	SCK9	-	-	-	-	-	-	-	-	-	-	LCD_DATA02_A
K4	123	K2	99	-	VCC	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
L4	124	K1	100	-	VSS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
L2	125	J3	101	68	-	KR07	P107	D07[A07/D07]	DQ07	AGTOA0	-	GTIOC8A	-	-	CTS8_RTS8/SS8	-	-	-	-	-	-	-	-	-	-	LCD_DATA01_A
M1	126	K3	102	69	-	KR06	P106	D06[A06/D06]	DQ06	AGTOB0	-	GTIOC8B	-	-	SCK8	-	-	SSLA3_A	-	-	-	-	-	-	-	-	LCD_DATA00_A
L3	127	J4	103	70	-	IRQ0/KR05	P105	D05[A05/D05]	DQ05	-	GTETRGA	GTIOC1A	-	-	TXD8/MOSI8/SDA8	-	-	SSLA2_A	-	-	-	-	-	-	-	-	LCD_TCON3_A
M2	128	L3	104	71	-	IRQ1/KR04	P104	D04[A04/D04]	DQ04	-	GTETRGB	GTIOC1B	-	-	RXD8/MISO8/SCL8	-	-	SSLA1_A	-	-	-	-	-	-	-	-	LCD_TCON2_A
N1	129	L1	105	72	-	KR03	P103	D03[A03/D03]	DQ03	-	GTOWUP	GTIOC2A_A	-	CTX0	CTS0_RTS0/SS0	-	-	SSLA0_A	-	-	-	-	-	-	-	-	LCD_TCON1_A
M3	130	M1	106	73	-	KR02	P102	D02[A02/D02]	DQ02	AGTO0	GTOWLO	GTIOC2B_A	-	CRX0	SCK0	-	-	RSPCKA_A	-	-	-	-	-	ADTRG0	-	-	LCD_TCON0_A
N2	131	M2	107	74	-	IRQ1/KR01	P101	D01[A01/D01]	DQ01	AGTEE0	GTETRGB	GTIOC5A	-	-	TXD0/MOSI0/SDA0	CTS1_RTS1/SS1	SDA1_B	MOSIA_A	-	-	-	-	-	-	-	-	LCD_CLK_A
P1	132	N1	108	75	-	IRQ2/KR00	P100	D00[A00/D00]	DQ00	AGTIO0	GTETRGA	GTIOC5B	-	-	RXD0/MISO0/SCL0	SCK1	SCL1_B	MISOA_A	-	-	-	-	-	-	-	-	LCD_EXTCLK_A
N3	133	L2	109	-	-	-	P800	D14[A14/D14]	DQ14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
R1	134	N2	110	-	-	-	P801	D15[A15/D15]	DQ15	-	-	-	-	-	-	-	-	-	-	-	-	-	SD1DAT4_A	-	-	-	-
P2	135	-	-	-	-	-	P802	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	SD1DAT5_A	-	-	-	LCD_DATA02_B
R2	136	-	-	-	-	-	P803	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	SD1DAT6_A	-	-	-	LCD_DATA01_B
P3	137	-	-	-		-	P804	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	SD1DAT7_A	-	-	-	LCD_DATA00_B
N4	138	N3	111	-	VCC	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
M4	139	M3	112	-	VSS	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
R3	140	K4	113	76	-	-	P500	-	-	AGTOA0	GTIU	GTIOC11A	-	USB_VBUSEN	-	-	-	QSPCLK	-	-	-	-	SD1CLK_A	AN016	IVREF0	-	-
P4	141	M4	114	77	-	IRQ11	P501	-	-	AGTOB0	GTIV	GTIOC11B	-	USB_OVRCURA	-	TXD5/MOSI5/SDA5	-	QSSL	-	-	-	-	SD1CMD_A	AN116	IVREF1	-	-
R4	142	L4	115	78	-	IRQ12	P502	-	-	-	GTIW	GTIOC12A	-	USB_OVRCURB	-	RXD5/MISO5/SCL5	-	QIO0	-	-	-	-	SD1DAT0_A	AN017	IVCMP0	-	-
N5	143	K5	116	79	-	-	P503	-	-	-	GTETRGC	GTIOC12B	-	USB_EXICEN	CTS6_RTS6/SS6	SCK5	-	QIO1	-	-	-	-	SD1DAT1_A	AN117	-	-	-
P5	144	L5	117	80	-	-	P504	ALE	-	-	GTETRGD	GTIOC13A	-	USB_ID	SCK6	CTS5_RTS5/SS5	-	QIO2	-	-	-	-	SD1DAT2_A	AN018	-	-	-
P6	145	K6	118	-	-	IRQ14	P505	-	-	-	-	GTIOC13B	-	-	RXD6/MISO6/SCL6	-	-	QIO3	-	-	-	-	SD1DAT3_A	AN118	-	-	-

2. Electrical Characteristics

Unless otherwise specified, the electrical characteristics of the MCU are defined under the following conditions:

VCC = AVCC0 = VCC_USB = VBATT = 2.7 to 3.6 V, 2.7 ≤ VREFH0/VREFH ≤ AVCC0, VCC_USBHS = AVCC_USBHS = 3.0 to 3.6 V, VSS = AVSS0 = VREFL0/VREFL = VSS_USB = VSS1_USBHS = VSS2_USBHS = PVSS_USBHS = AVSS_USBHS = 0 V, Ta = Topr

Figure 2.1 shows the timing conditions.

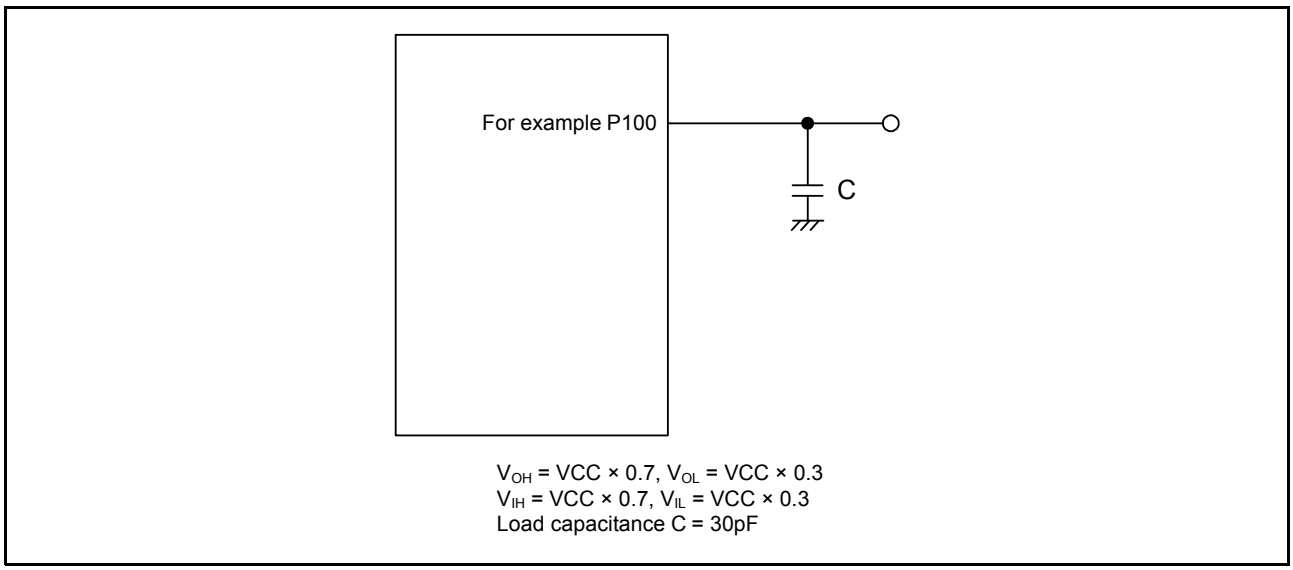


Figure 2.1 Input or output timing measurement conditions

The measurement conditions of timing specification in each peripherals are recommended for the best peripheral operation, however make sure to adjust driving abilities of each pins to meet your conditions.

2.1 Absolute Maximum Ratings

Table 2.1 Absolute maximum ratings

Item	Symbol	Value	Unit
Power supply voltage	VCC, VCC_USB *2	–0.3 to +4.0	V
VBATT power supply voltage	VBATT	–0.3 to +4.0	V
Input voltage (except for 5V-tolerant ports*1)	V_{in}	–0.3 to VCC + 0.3	V
Input voltage (5V-tolerant ports*1)	V_{in}	–0.3 to + VCC + 4.0 (max 5.8)	V
Reference power supply voltage	VREFH/VREFH0	–0.3 to VCC + 0.3	V
Analog power supply voltage	AVCC0 *2	–0.3 to +4.0	V
USBHS power supply voltage	VCC_USBHS	–0.3 to +4.0	V
USBHS analog power supply voltage	AVCC_USBHS	–0.3 to +4.0	V
Analog input voltage	V_{AN}	–0.3 to AVCC0 + 0.3	V
Operating temperature*3,*4,*5	T_{opr}	–40 to +85 –40 to +105	°C
Storage temperature	T_{stg}	–55 to +125	°C

Caution: Permanent damage to the MCU might result if absolute maximum ratings are exceeded.

Note 1. Ports P205, P206, P400, P401, P407 to P415, P511, P512, P708 to P713, and PB01 are 5V-tolerant.
Note 2. Connect AVCC0 and VCC_USB to VCC.
Note 3. See section 2.2.1, T_j/T_a Definition.
Note 4. Contact a Renesas Electronics sales office for information on derating operation when T_a = +85°C to +105°C. Derating is the systematic reduction of load for improved reliability.
Note 5. The upper limit of operating temperature is 85°C or 105°C, depending on the product. For details, see section 1.3, Part Numbering.

2.2.5 Operating and Standby Current

Table 2.7 Operating and standby current (1 of 2)

Item				Symbol	Min	Typ	Max	Unit	Test conditions
Supply current*1	High-speed mode	Maximum*2		I_{CC}*3	-	-	137*2	mA	ICLK = 120 MHz PCLKA = 120 MHz*7 PCLKB = 60 MHz PCLKC = 60 MHz PCLKD = 120 MHz FCLK = 60 MHz BCLK = 120 MHz
		CoreMark®*5			-	21	-		
		Normal mode	All peripheral clocks enabled, while (1) code executing from flash*4		-	34	-		
			All peripheral clocks disabled, while (1) code executing from flash*5, *6		-	14	-		
		Sleep mode*5, *6			-	12	46		
		Increase during BGO operation	Data flash P/E		-	6	-		
			Code flash P/E		-	8	-		
	Low-speed mode*5				-	2.4	-		ICLK = 1 MHz
	Subosc-speed mode*5				-	2	-		ICLK = 32.768 kHz
	Software Standby mode				-	1.8	28		-
	Deep Software Standby mode	Power supplied to Standby SRAM and USB resume detecting unit			-	30	113	µA	-
		Power not supplied to SRAM or USB resume detecting unit	Power-on reset circuit low-power function disabled		-	13	40		-
			Power-on reset circuit low-power function enabled		-	6.3	34		-
		Increase when the RTC and AGT are operating	When the low-speed on-chip oscillator (LOCO) is in use		-	5	-		-
			When a crystal oscillator for low clock loads is in use		-	1.0	-		-
			When a crystal oscillator for standard clock loads is in use		-	1.5	-		-
	RTC operating while VCC is off (with the battery backup function, only the RTC and sub-clock oscillator operate)		When a crystal oscillator for low clock loads is in use		-	0.9	-		V_{BATT} = 1.8 V, VCC = 0 V
					-	1.3	-		V_{BATT} = 3.3 V, VCC = 0 V
			When a crystal oscillator for standard clock loads is in use		-	1.1	-		V_{BATT} = 1.8 V, VCC = 0 V
					-	1.8	-		V_{BATT} = 3.3 V, VCC = 0 V
Analog power supply current	During 12-bit A/D conversion			AI_{CC}	-	0.8	1.1	mA	-
	During 12-bit A/D conversion with S/H amp				-	2.3	3.3	mA	-
	PGA (1ch)				-	1	3	mA	-
	ACMPHS (1unit)				-	100	150	µA	AVCC ≥ 2.7 V
	Temperature sensor				-	0.1	0.2	mA	-
	During D/A conversion (per unit)		Without AMP output		-	0.1	0.2	mA	-
			With AMP output		-	0.6	1.1	mA	-
	Waiting for A/D, D/A conversion (all units)				-	0.9	1.6	mA	-
	ADC12, DAC12 in standby modes (all units)*8				-	2	8	µA	-
Reference power supply current (VREFH0)	During 12-bit A/D conversion (unit 0)			AI_{REFH0}	-	70	120	µA	-
	Waiting for 12-bit A/D conversion (unit 0)				-	0.07	0.5	µA	-
	ADC12 in standby modes (unit 0)				-	0.07	0.5	µA	-
Reference power supply current (VREFH)	During 12-bit A/D conversion (unit 1)			AI_{REFH}	-	70	120	µA	-
	During D/A conversion (per unit)		Without AMP output		-	0.1	0.4	mA	-
			With AMP ouput		-	0.1	0.4	mA	-
	Waiting for 12-bit A/D (unit 1), D/A (all units) conversion				-	0.07	0.8	µA	-
	ADC12 unit 1 in standby modes				-	0.07	0.8	µA	-

Note 1. FCLK must run at a frequency of at least 4 MHz when programming or erasing the flash memory.
Note 2. See section 9, Clock Generation Circuit in User's Manual for the relationship between the ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK frequencies.
Note 3. When the ADC12 is used, the PCLKC frequency must be at least 1 MHz.

Table 2.11 Operation frequency value in low-speed mode

Item		Symbol	Min	Typ	Max	Unit
Operation frequency	System clock (ICLK)*2	f	-	-	1	MHz
	Peripheral module clock (PCLKA)*2		-	-	1	
	Peripheral module clock (PCLKB)*2		-	-	1	
	Peripheral module clock (PCLKC)*2,*3		-*3	-	1	
	Peripheral module clock (PCLKD)*2		-	-	1	
	Flash interface clock (FCLK)*1, *2		-	-	1	
	External bus clock (BCLK)		-	-	1	
	EBCLK pin output		-	-	1	

Note 1. Programming or erasing the flash memory is disabled in low-speed mode.
Note 2. See section 9, Clock Generation Circuit in User's Manual for the relationship between the ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK frequencies.
Note 3. When the ADC12 is used, the PCLKC frequency must be set to at least 1 MHz.

Table 2.12 Operation frequency value in Subosc-speed mode

Item		Symbol	Min	Typ	Max	Unit
Operation frequency	System clock (ICLK)*2	f	27.8	-	37.7	kHz
	Peripheral module clock (PCLKA)*2		-	-	37.7	
	Peripheral module clock (PCLKB)*2		-	-	37.7	
	Peripheral module clock (PCLKC)*2,*3		-	-	37.7	
	Peripheral module clock (PCLKD)*2		-	-	37.7	
	Flash interface clock (FCLK)*1, *2		27.8	-	37.7	
	External bus clock (BCLK)*2		-	-	37.7	
	EBCLK pin output		-	-	37.7	

Note 1. Programming or erasing the flash memory is disable in Subosc-speed mode.
Note 2. See section 9, Clock Generation Circuit in User's Manual for the relationship between the ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK frequencies.
Note 3. The ADC12 cannot be used.

2.3.2 Clock Timing

Table 2.13 Clock timing except for sub-clock oscillator (1 of 2)

Item	Symbol	Min	Typ	Max	Unit	Test conditions
EBCLK pin output cycle time	t_{Bcyc}	16.6	-	-	ns	Figure 2.3
EBCLK pin output high pulse width	t_{CH}	3.3	-	-	ns	
EBCLK pin output low pulse width	t_{CL}	3.3	-	-	ns	
EBCLK pin output rise time	t_{Cr}	-	-	5.0	ns	
EBCLK pin output fall time	t_{Cf}	-	-	5.0	ns	
SDCLK pin output cycle time	t_{SDcyc}	8.33	-	-	ns	
SDCLK pin output high pulse width	t_{CH}	1.0	-	-	ns	
SDCLK pin output low pulse width	t_{CL}	1.0	-	-	ns	
SDCLK pin output rise time	t_{Cr}	-	-	3.0	ns	
SDCLK pin output fall time	t_{Cf}	-	-	3.0	ns	

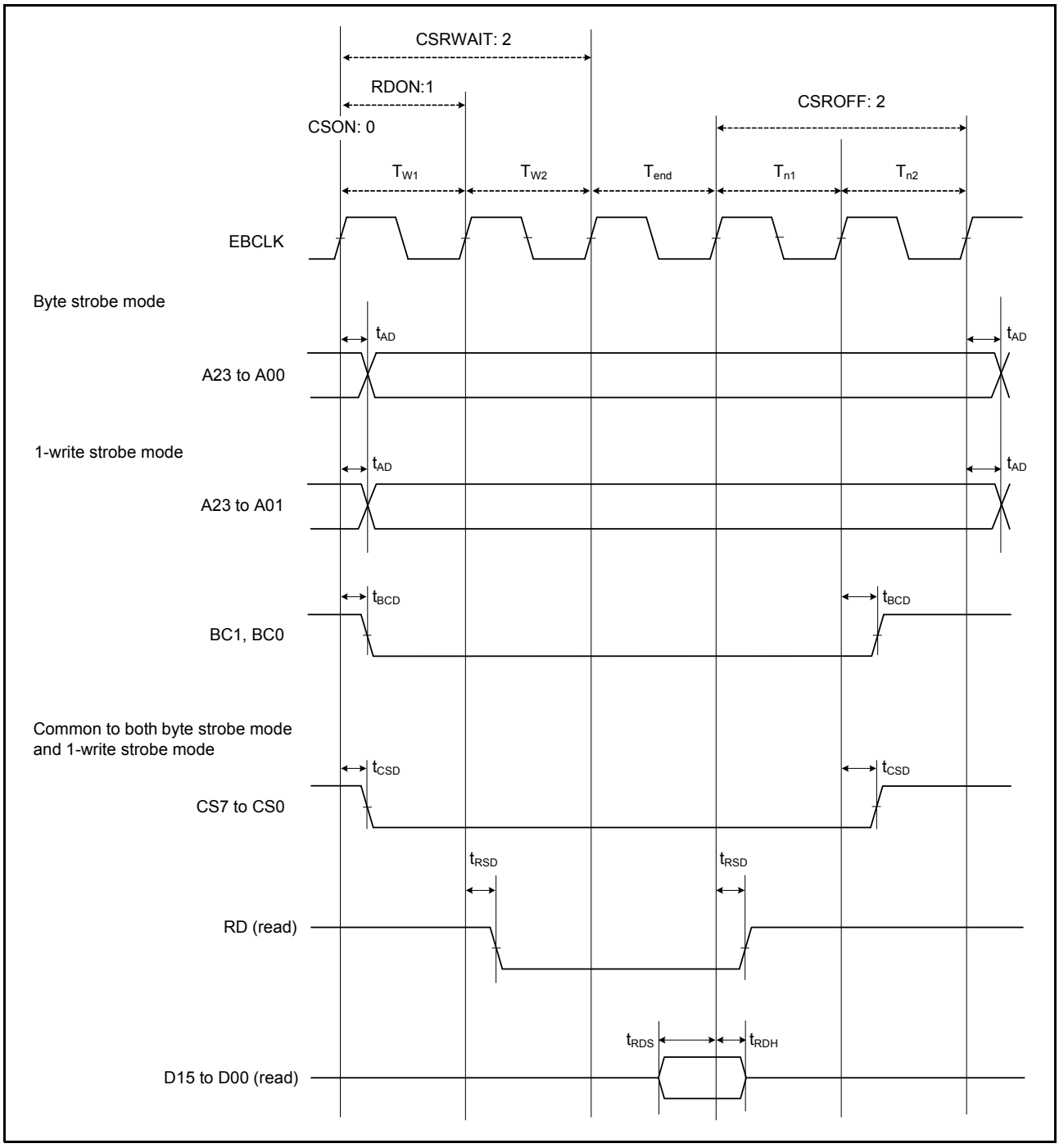
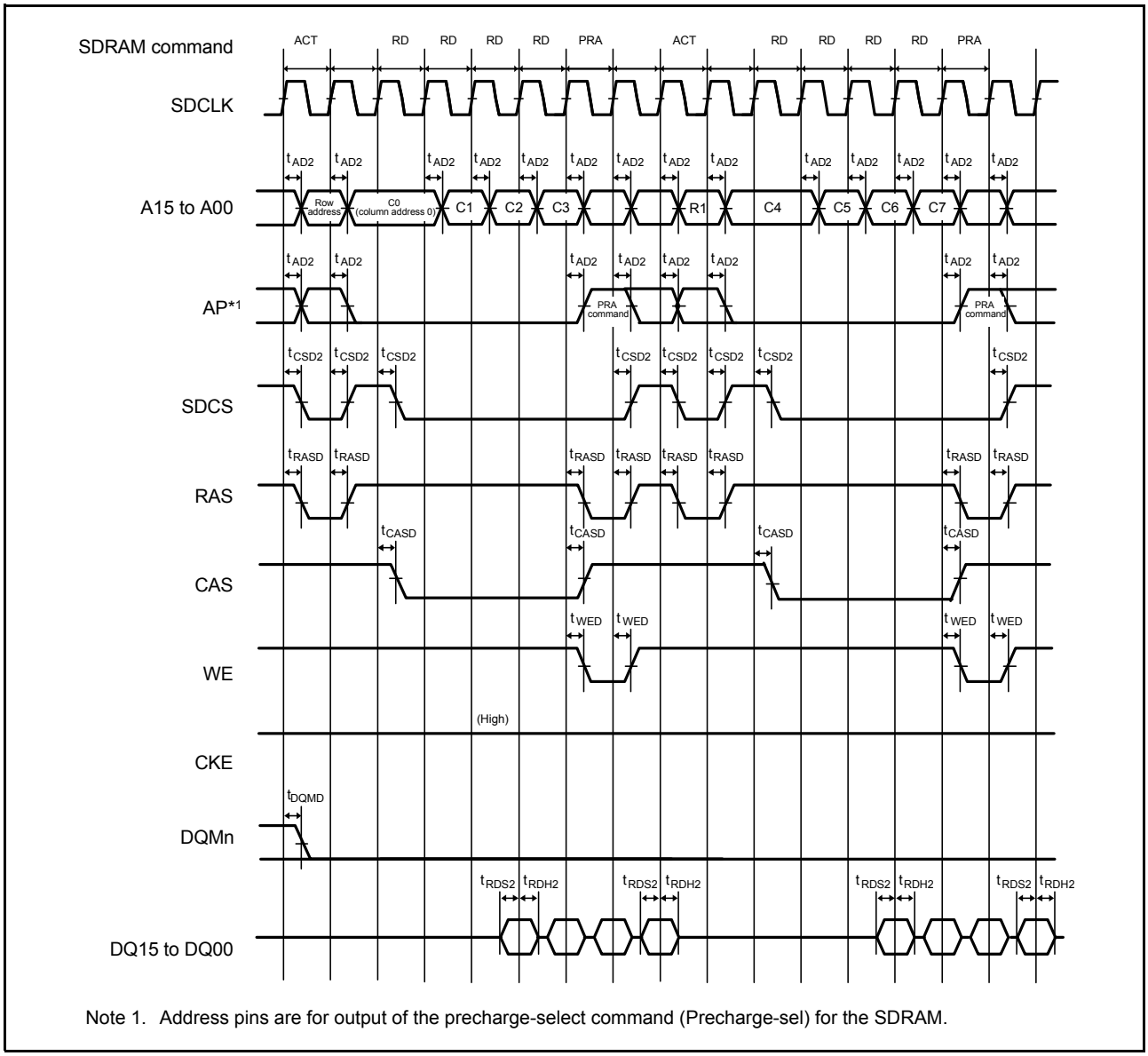


Figure 2.18 External bus timing for normal read cycle with bus clock synchronized



Note 1. Address pins are for output of the precharge-select command (Precharge-sel) for the SDRAM.

Figure 2.27 SDRAM multiple read line stride timing

Table 2.19 I/O ports, POEG, GPT32, AGT, KINT, and ADC12 trigger timing (2 of 2)

GPT32 Conditions:
High drive output is selected in the port drive capability bit in the PmnPFS register.

AGT Conditions:
Middle drive output is selected in the port drive capability bit in the PmnPFS register.

Item			Symbol	Min	Max	Unit	Test conditions
GPT32	Input capture pulse width	Single edge	t_{GTICW}	1.5	-	t_{PDcyc}	Figure 2.32
		Dual edge		2.5	-		
	GTIOCxY output skew (x = 0 to 7, Y= A or B)	Middle drive buffer	t_{GTISK}*2	-	4	ns	Figure 2.33
		High drive buffer		-	4		
	GTIOCxY output skew (x = 8 to 13, Y = A or B)	Middle drive buffer		-	4		
		High drive buffer		-	4		
	GTIOCxY output skew (x = 0 to 13, Y = A or B)	Middle drive buffer		-	6		
		High drive buffer		-	6		
	OPS output skew GTOUUP, GTOULO, GTOVUP, GTOVLO, GTOWUP, GTOWLO		t_{GTOSK}	-	5	ns	Figure 2.34
GPT(PWM Delay Generation Circuit)	GTIOCxY_Z output skew (x = 0 to 3, Y = A or B, Z = A)		t_{HRSK}*3	-	2.0	ns	Figure 2.35
AGT	AGTIO, AGTEE input cycle		t_{ACYC}*4	100	-	ns	Figure 2.36
	AGTIO, AGTEE input high width, low width		t_{ACKWH}, t_{ACKWL}	40	-	ns	
	AGTIO, AGTO, AGTOA, AGTOB output cycle		t_{ACYC2}	62.5	-	ns	
ADC12	ADC12 trigger input pulse width		t_{TRGW}	1.5	-	t_{Pcyc}	Figure 2.37
KINT	Key interrupt input low width		t_{KR}	250	-	ns	Figure 2.38

Note 1. t_{Pcyc}: PCLKB cycle, t_{PDcyc}: PCLKD cycle.
Note 2. This skew applies when the same driver I/O is used. If the I/O of the middle and high drivers is mixed, operation is not guaranteed.
Note 3. The load is 30 pF.
Note 4. Constraints on AGTIO input: $t_{Pcyc} \times 2$ (t_{Pcyc}: PCLKB cycle) < t_{ACYC}.

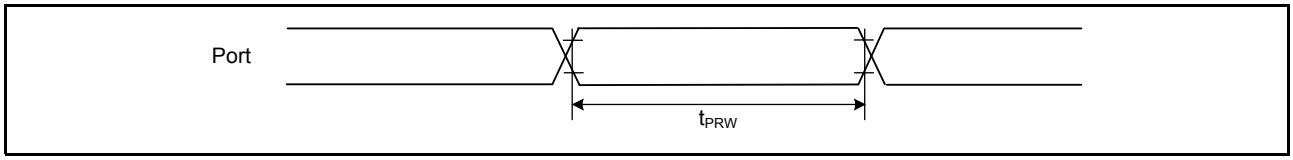


Figure 2.30 I/O ports input timing

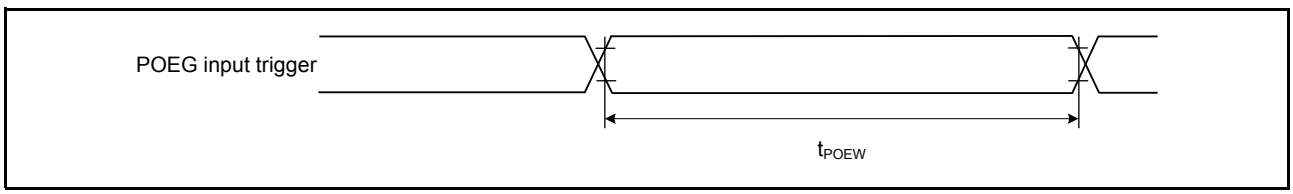


Figure 2.31 POEG input trigger timing

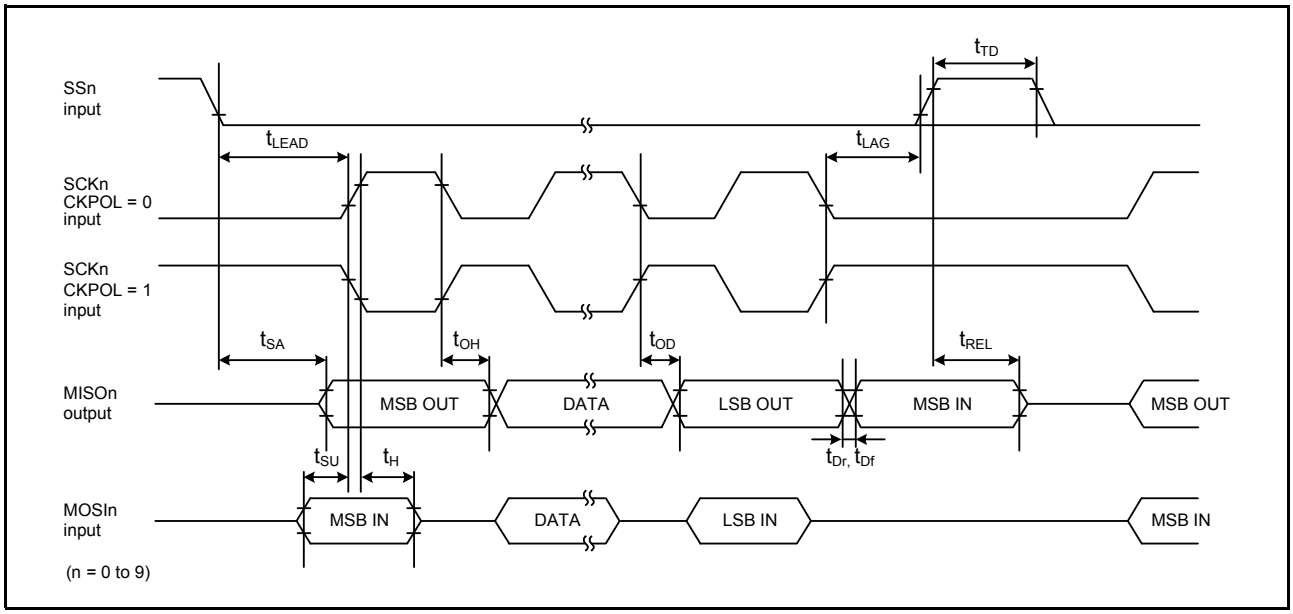


Figure 2.44 SCI simple SPI mode timing for slave when CKPH = 1

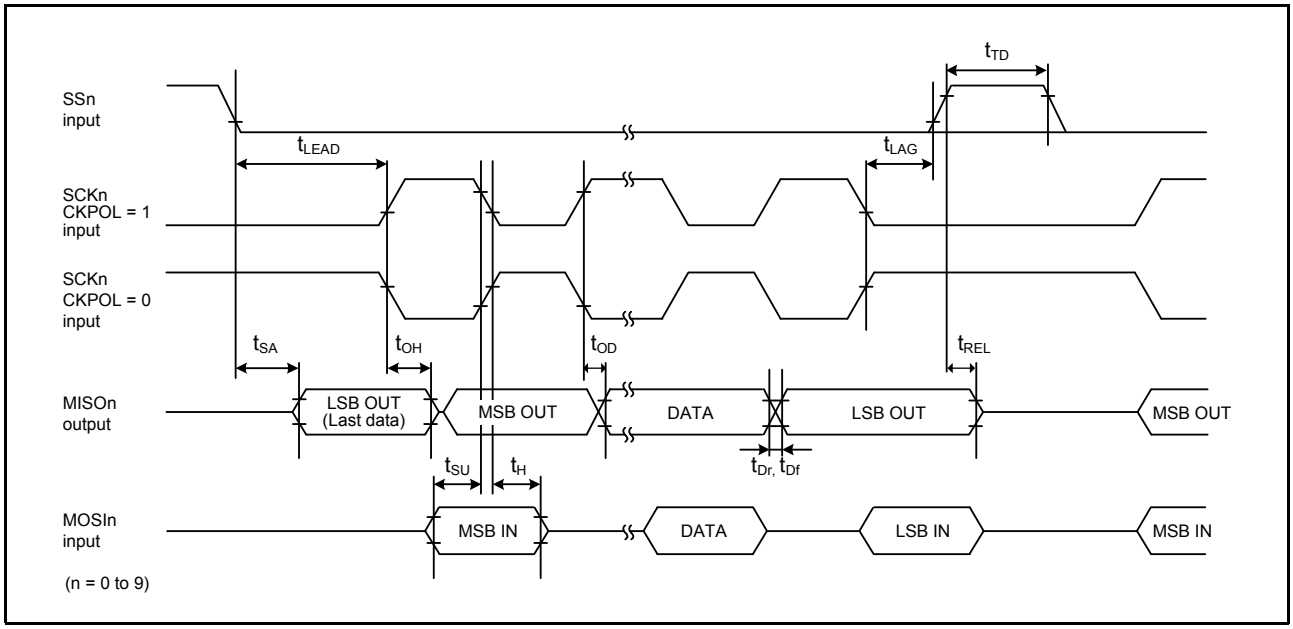


Figure 2.45 SCI simple SPI mode timing for slave when CKPH = 0

Table 2.24 SCI timing (3) (1 of 2)
Conditions: Middle drive output is selected in the port drive capability bit in the PmnPFS register.

Item		Symbol	Min	Max	Unit	Test conditions
Simple IIC (Standard mode)	SDA input rise time	t_{Sr}	-	1000	ns	Figure 2.46
	SDA input fall time	t_{Sf}	-	300	ns	
	SDA input spike pulse removal time	t_{SP}	0	4 × t_{IICcyc}	ns	
	Data input setup time	t_{SDAS}	250	-	ns	
	Data input hold time	t_{SDAH}	0	-	ns	
	SCL, SDA capacitive load	C_{b}*1	-	400	pF	

Note 2. Must use pins that have a letter (“_A”, “_B”) to indicate group membership appended to their name as groups. For the SPI interface, the AC portion of the electrical characteristics is measured for each group.
Note 3. N is set to an integer from 1 to 8 by the SPCKD register.
Note 4. N is set to an integer from 1 to 8 by the SSLND register.

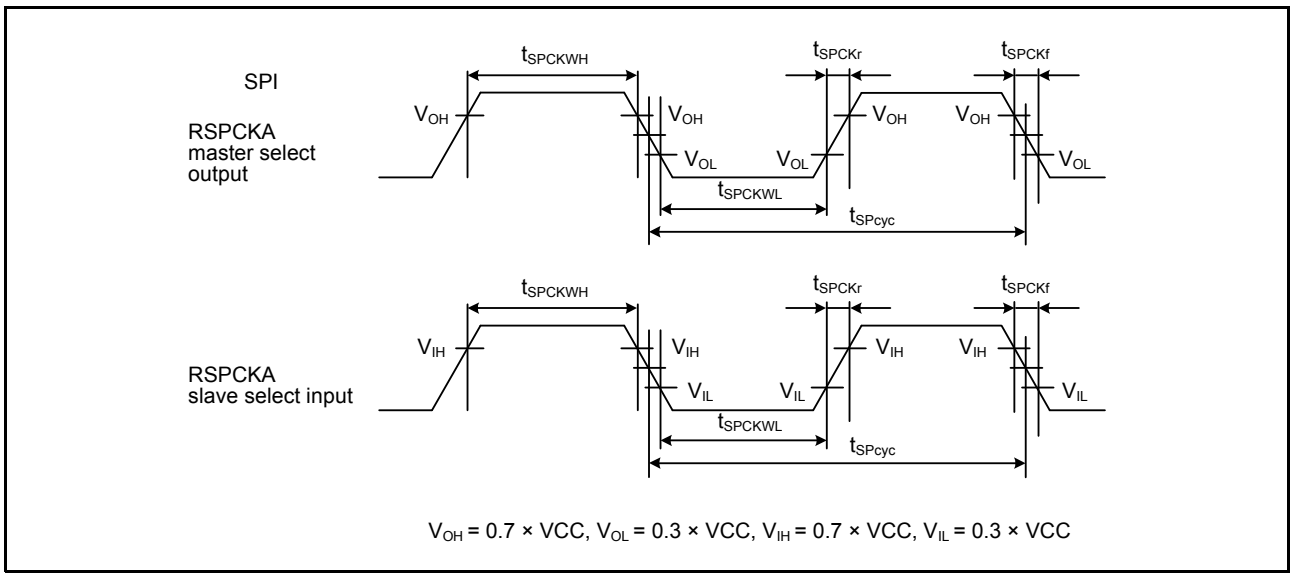


Figure 2.47 SPI clock timing

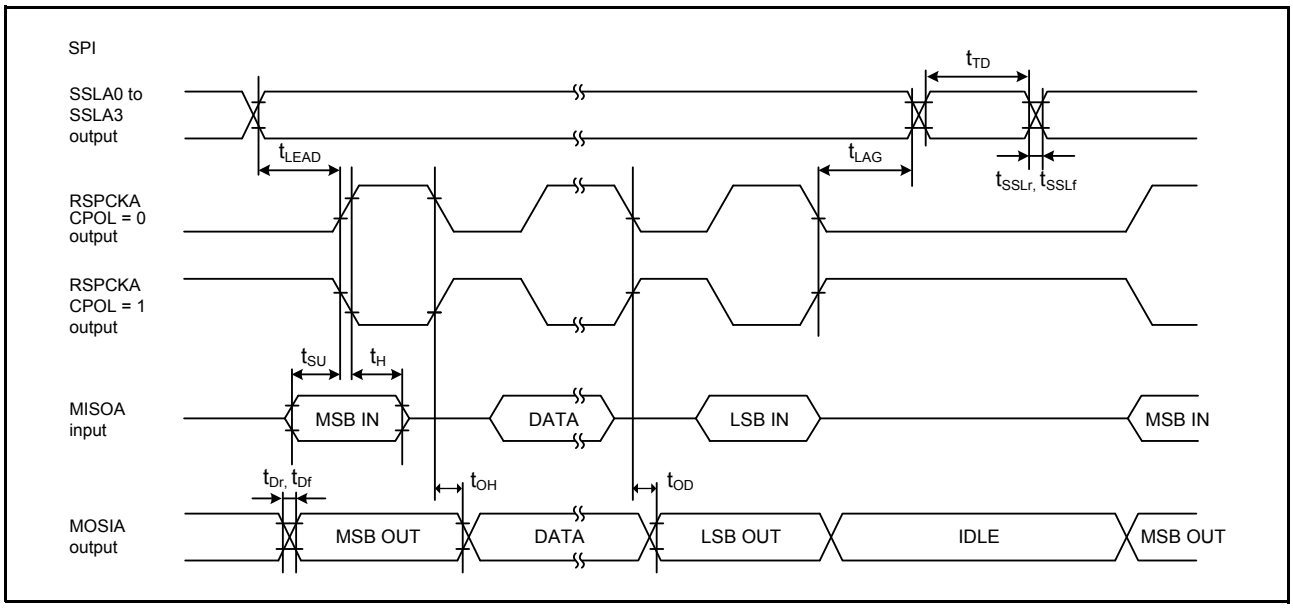


Figure 2.48 SPI timing for master when CPHA = 0

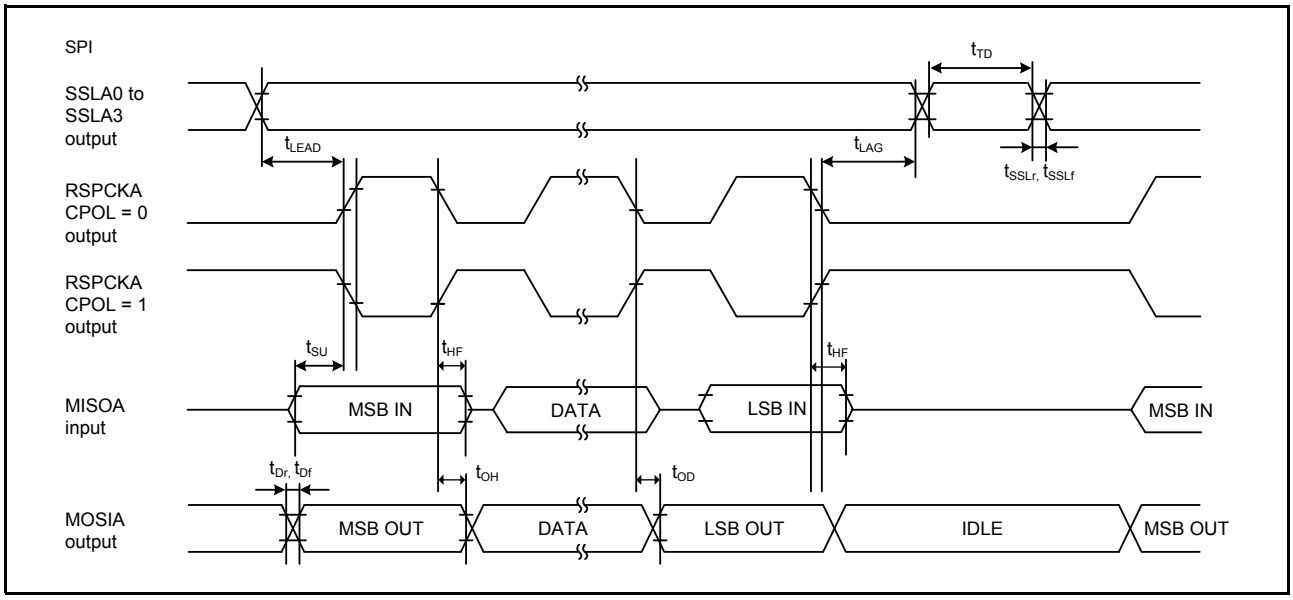


Figure 2.49 SPI timing for master when CPHA = 0 and the bit rate is set to PCLKA/2

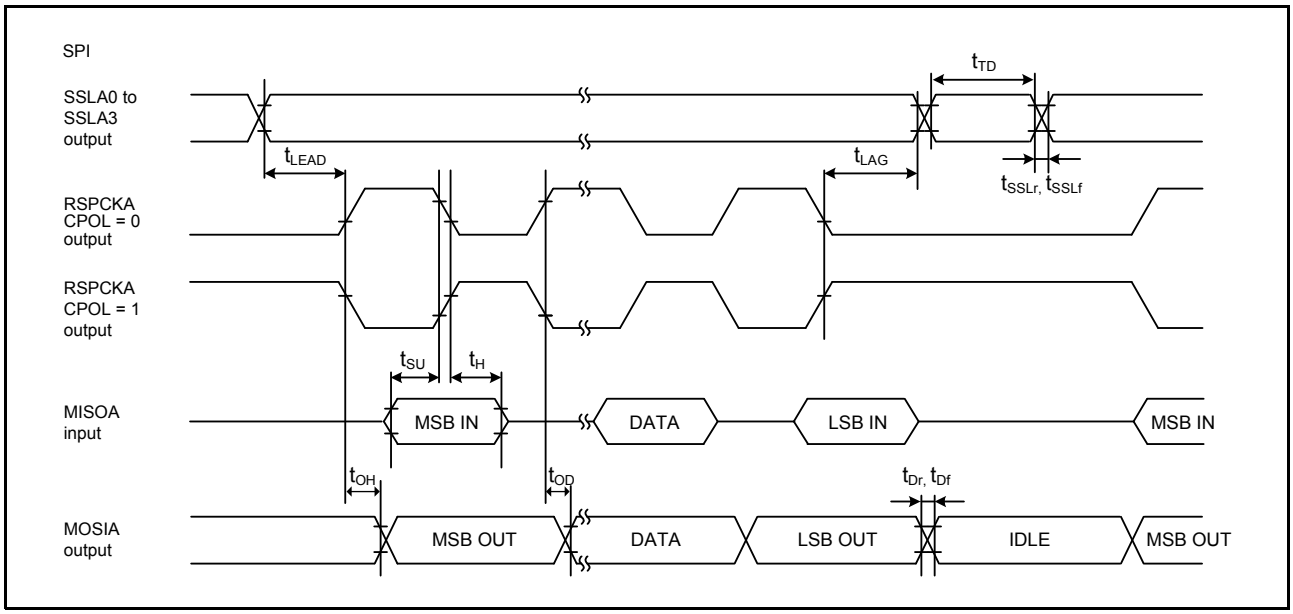


Figure 2.50 SPI timing for master when CPHA = 1

2.3.14 SSIE Timing

Table 2.29 SSIE timing

(1) High drive output is selected with the port drive capability bit in the PmnPFS register.

(2) Use pins that have a letter appended to their names, for instance "_A" or "_B" to indicate group membership. For the SSIE interface, the AC portion of the electrical characteristics is measured for each group.

Item			Symbol	Target specification		Unit	Comments
				Min.	Max.		
SSIBCK	Cycle	Master	t_O	80	-	ns	Figure 2.57
		Slave	t_I	80	-	ns	
	High level/ low level	Master	t_{HC}/t_{LC}	0.35	-	t_O	
		Slave		0.35	-	t_I	
	Rising time/falling time	Master	t_{RC}/t_{FC}	-	0.15	t_O / t_I	
		Slave		-	0.15	t_O / t_I	
SSILRCK/SSIFS, SSITXD0, SSIRXD0, SSIDATA1	Input set up time	Master	t_{SR}	12	-	ns	Figure 2.59, Figure 2.60
		Slave		12	-	ns	
	Input hold time	Master	t_{HR}	8	-	ns	
		Slave		15	-	ns	
	Output delay time	Master	t_{DTR}	-10	5	ns	
		Slave		0	20	ns	Figure 2.59, Figure 2.60
	Output delay time from SSILRCK/SSIFS change	Slave	t_{DTRW}	-	20	ns	Figure 2.61*1
GTIOC1A, AUDIO_CLK	Cycle		t_{EXcyc}	20	-	ns	Figure 2.58
	High level/ low level		t_{EXL}/ t_{EXH}	0.4	0.6	t_{EXcyc}	

Note 1. For slave-mode transmission, SSIE has a path, through which the signal input from the SSILRCK/SSIFS pin is used to generate transmit data, and the transmit data is logically output to the SSITXD0 or SSIDATA1 pin.

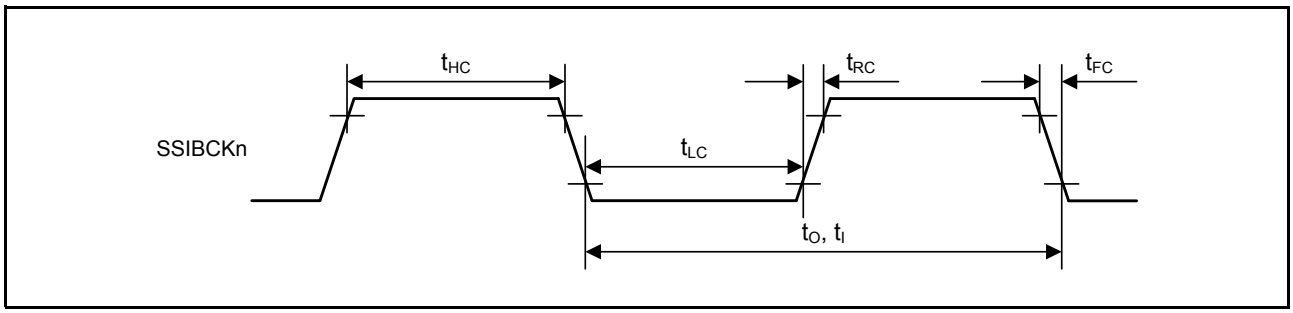


Figure 2.57 SSIE clock input/output timing

Offset error

Offset error is the difference between the transition point of the ideal first output code and the actual first output code.

Full-scale error

Full-scale error is the difference between the transition point of the ideal last output code and the actual last output code.

2.6 DAC12 Characteristics

Table 2.44 D/A conversion characteristics

Item	Min	Typ	Max	Unit	Test conditions
Resolution	-	-	12	Bits	-
Without output amplifier					
Absolute accuracy	-	-	±24	LSB	Resistive load 2 MΩ
INL	-	±2.0	±8.0	LSB	Resistive load 2 MΩ
DNL	-	±1.0	±2.0	LSB	-
Output impedance	-	8.5	-	kΩ	-
Conversion time	-	-	3.0	µs	Resistive load 2 MΩ, Capacitive load 20 pF
Output voltage range	0	-	VREFH	V	-
With output amplifier					
INL	-	±2.0	±4.0	LSB	-
DNL	-	±1.0	±2.0	LSB	-
Conversion time	-	-	4.0	µs	-
Resistive load	5	-	-	kΩ	-
Capacitive load	-	-	50	pF	-
Output voltage range	0.2	-	VREFH – 0.2	V	-

2.7 TSN Characteristics

Table 2.45 TSN characteristics

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Relative accuracy	-	-	±1.0	-	°C	-
Temperature slope	-	-	4.0	-	mV/°C	-
Output voltage (at 25°C)	-	-	1.24	-	V	-
Temperature sensor start time	t_{START}	-	-	30	µs	-
Sampling time	-	4.15	-	-	µs	-

2.8 OSC Stop Detect Characteristics

Table 2.46 Oscillation stop detection circuit characteristics

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Detection time	t_{dr}	-	-	1	ms	Figure 2.92

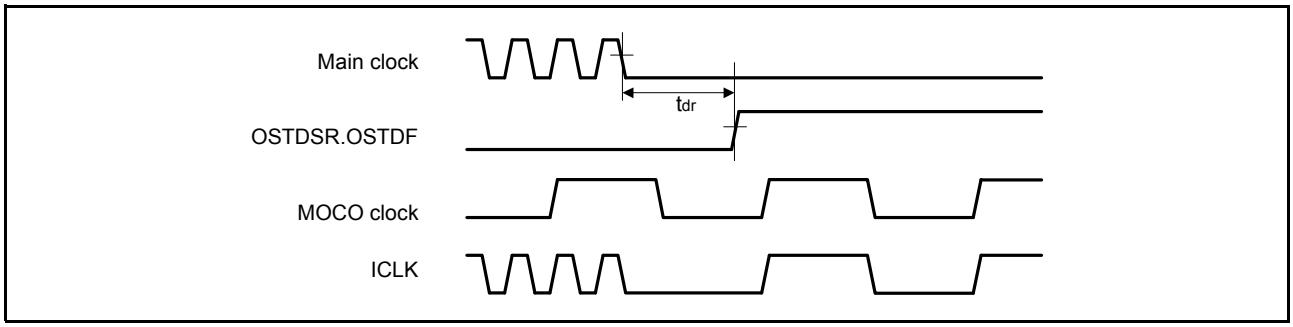


Figure 2.92 Oscillation stop detection timing

2.9 POR and LVD Characteristics

Table 2.47 Power-on reset circuit and voltage detection circuit characteristics

Item			Symbol	Min	Typ	Max	Unit	Test conditions
Voltage detection level	Power-on reset (POR)	Module-stop function disabled*2	V_{POR}	2.5	2.6	2.7	V	Figure 2.93
		Module-stop function enabled*3		1.8	2.25	2.7		
	Voltage detection circuit (LVD0)		V_{det0_1}	2.84	2.94	3.04		Figure 2.94
			V_{det0_2}	2.77	2.87	2.97		
			V_{det0_3}	2.70	2.80	2.90		
	Voltage detection circuit (LVD1)		V_{det1_1}	2.89	2.99	3.09		Figure 2.95
			V_{det1_2}	2.82	2.92	3.02		
			V_{det1_3}	2.75	2.85	2.95		
	Voltage detection circuit (LVD2)		V_{det2_1}	2.89	2.99	3.09		Figure 2.96
			V_{det2_2}	2.82	2.92	3.02		
			V_{det2_3}	2.75	2.85	2.95		
Internal reset time	Power-on reset time		t_{POR}	-	4.5	-	ms	Figure 2.93
	LVD0 reset time		t_{LVD0}	-	0.51	-		Figure 2.94
	LVD1 reset time		t_{LVD1}	-	0.38	-		Figure 2.95
	LVD2 reset time		t_{LVD2}	-	0.38	-		Figure 2.96
Minimum VCC down time*1			t_{VOFF}	200	-	-	µs	Figure 2.93, Figure 2.94
Response delay			t_{det}	-	-	200	µs	Figure 2.93 to Figure 2.96
LVD operation stabilization time (after LVD is enabled)			$t_{d(E-A)}$	-	-	10	µs	Figure 2.95, Figure 2.96
Hysteresis width (LVD1 and LVD2)			V_{LVH}	-	70	-	mV	

Note 1. The minimum VCC down time indicates the time when VCC is below the minimum value of voltage detection levels V_{POR}, V_{det1}, and V_{det2} for POR and LVD.
Note 2. The low-power function is disabled and DEEPCUT[1:0] = 00b or 01b.
Note 3. The low-power function is enabled and DEEPCUT[1:0] = 11b.

2.13 PGA Characteristics

Table 2.51 PGA characteristics in single mode

Item	Symbol	Min	Typ	Max	Unit
PGAVSS input voltage range	PGAVSS	0	-	0	V
	AIN0 (G = 2.000)	0.050 × AVCC0	-	0.45 × AVCC0	V
	AIN1 (G = 2.500)	0.047 × AVCC0	-	0.360 × AVCC0	V
	AIN2 (G = 2.667)	0.046 × AVCC0	-	0.337 × AVCC0	V
	AIN3 (G = 2.857)	0.046 × AVCC0	-	0.32 × AVCC0	V
	AIN4 (G = 3.077)	0.045 × AVCC0	-	0.292 × AVCC0	V
	AIN5 (G = 3.333)	0.044 × AVCC0	-	0.265 × AVCC0	V
	AIN6 (G = 3.636)	0.042 × AVCC0	-	0.247 × AVCC0	V
	AIN7 (G = 4.000)	0.040 × AVCC0	-	0.212 × AVCC0	V
	AIN8 (G = 4.444)	0.036 × AVCC0	-	0.191 × AVCC0	V
	AIN9 (G = 5.000)	0.033 × AVCC0	-	0.17 × AVCC0	V
	AIN10 (G = 5.714)	0.031 × AVCC0	-	0.148 × AVCC0	V
	AIN11 (G = 6.667)	0.029 × AVCC0	-	0.127 × AVCC0	V
	AIN12 (G = 8.000)	0.027 × AVCC0	-	0.09 × AVCC0	V
	AIN13 (G = 10.000)	0.025 × AVCC0	-	0.08 × AVCC0	V
	AIN14 (G = 13.333)	0.023 × AVCC0	-	0.06 × AVCC0	V
Gain error	Gerr0 (G = 2.000)	–1.0	-	1.0	%
	Gerr1 (G = 2.500)	–1.0	-	1.0	%
	Gerr2 (G = 2.667)	–1.0	-	1.0	%
	Gerr3 (G = 2.857)	–1.0	-	1.0	%
	Gerr4 (G = 3.077)	–1.0	-	1.0	%
	Gerr5 (G = 3.333)	–1.5	-	1.5	%
	Gerr6 (G = 3.636)	–1.5	-	1.5	%
	Gerr7 (G = 4.000)	–1.5	-	1.5	%
	Gerr8 (G = 4.444)	–2.0	-	2.0	%
	Gerr9 (G = 5.000)	–2.0	-	2.0	%
	Gerr10 (G = 5.714)	–2.0	-	2.0	%
	Gerr11 (G = 6.667)	–2.0	-	2.0	%
	Gerr12 (G = 8.000)	–2.0	-	2.0	%
	Gerr13 (G = 10.000)	–2.0	-	2.0	%
	Gerr14 (G = 13.333)	–2.0	-	2.0	%
Offset error	Voff	–8	-	8	mV

Table 2.52 PGA characteristics in differential mode (1 of 2)

Item		Symbol	Min	Typ	Max	Unit
PGAVSS input voltage range		PGAVSS	–0.5	-	0.3	V
Differential input voltage range	G = 1.500	AIN-PGAVSS	–0.5	-	0.5	V
	G = 2.333		–0.4	-	0.4	V
	G = 4.000		–0.2	-	0.2	V
	G = 5.667		–0.15	-	0.15	V

Table 2.54 Data flash memory characteristics (2 of 2)
Conditions: Program or erase: FCLK = 4 to 60 MHz
Read: FCLK ≤ 60 MHz

Item		Symbol	FCLK = 4 MHz			20 MHz ≤ FCLK ≤ 60 MHz			Unit	Test conditions
			Min	Typ	Max	Min	Typ	Max		
Suspend delay during programming	4-byte	t_{DSPD}	-	-	264	-	-	120	µs	
	8-byte		-	-	264	-	-	120		
	16-byte		-	-	264	-	-	120		
First suspend delay during erasure in suspend priority mode	64-byte	t_{DSESD1}	-	-	216	-	-	120	µs	
	128-byte		-	-	216	-	-	120		
	256-byte		-	-	216	-	-	120		
Second suspend delay during erasure in suspend priority mode	64-byte	t_{DSESD2}	-	-	300	-	-	300	µs	
	128-byte		-	-	390	-	-	390		
	256-byte		-	-	570	-	-	570		
Suspend delay during erasing in erasure priority mode	64-byte	t_{DSEED}	-	-	300	-	-	300	µs	
	128-byte		-	-	390	-	-	390		
	256-byte		-	-	570	-	-	570		
Forced stop command		t_{FD}	-	-	32	-	-	20	µs	
Data hold time*3		t_{DRP}	10*3,*4	-	-	10*3,*4	-	-	Year	
			30*3,*4	-	-	30*3,*4	-	-		Ta = +85°C

Note 1. The reprogram/erase cycle is the number of erasures for each block. When the reprogram/erase cycle is n times (n = 125,000), erasing can be performed n times for each block. For example, when 4-byte programming is performed 16 times for different addresses in 64-byte blocks, and then the entire block is erased, the reprogram/erase cycle is counted as one. However, programming the same address several times as one erasure is not enabled. (Overwriting is prohibited.)
Note 2. This is the minimum number of times to guarantee all the characteristics after reprogramming. The guaranteed range is from 1 to the minimum value.
Note 3. This indicates the minimum value of the characteristic when reprogramming is performed within the specified range.
Note 4. This result is obtained from reliability testing.

2.15 Boundary Scan

Table 2.55 Boundary scan characteristics

Item	Symbol	Min	Typ	Max	Unit	Test conditions
TCK clock cycle time	t_{TCKcyc}	100	-	-	ns	Figure 2.99
TCK clock high pulse width	t_{TCKH}	45	-	-	ns	
TCK clock low pulse width	t_{TCKL}	45	-	-	ns	
TCK clock rise time	t_{TCKr}	-	-	5	ns	
TCK clock fall time	t_{TCKf}	-	-	5	ns	
TMS setup time	t_{TMSS}	20	-	-	ns	Figure 2.100
TMS hold time	t_{TMSH}	20	-	-	ns	
TDI setup time	t_{TDIS}	20	-	-	ns	
TDI hold time	t_{TDIH}	20	-	-	ns	
TDO data delay	t_{TDOD}	-	-	40	ns	
Boundary scan circuit startup time*1	T_{BSSTUP}	t_{RESWP}	-	-	-	Figure 2.101

Note 1. Boundary scan does not function until the power-on reset becomes negative.

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